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Safety and Reliability of Embedded Systems (Sicherheit und Zuverlässigkeit eingebetteter Systeme) Safety and Reliability Analysis Models: Overview

Content



- Classification
- Hazard and Operability Study (HAZOP)
- Preliminary Hazard Analysis (PHA)
- Event Tree Analysis
- Failure Modes Effects and Criticality Analysis (FMECA) (DIN 25448, IEC 812)
- Reliability Block Diagrams (IEC 61078)
- Fault Tree Analysis (DIN 25424, IEC 61025)
- Markov Analysis (IEC 61165)
 - Markov Chain
 - Markov Processes
- Petri Nets
 - Condition/Event Petri nets
 - State/Transition Petri nets
 - Predicate/Transistion Petri Nets / Coloured Petri Nets
 - Timed Petri Net Types
 - SPN
 - GSPN
 - DSPN



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Classification of Safety / Reliability Analysis Techniques



- Focused Property
 - Safety, Reliability, Availability...
- Application Area
- Scope
 - Product / Process, HW / SW, System / Component
- Process Phase
- Search Direction
 - Inductive / Deductive
- Degree of Formality
- Representation
 - Textual, Graphical, Tabular
- Model based: Combinatorial vs. State-Based



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Hazard and Operability Study (HAZOP)

- From chemical industry
- Find potential hazards at early process stage
- Check every "flow" in preliminary design scheme for deviations
- Manual search using guide-words (more, less, no, reverse...)
- Preliminary Hazard Analysis (PHA)
 - During requirements analysis or early design phase
 - Coarse identification, classification and counter-measures for potential hazards
 - Table representations



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- Forward-searching technique with graphical representation
- Search consequences to given hazard, depending on conditions

	Pressure Relief Valve 1	Pressure Relief Valve 2	
Pres <u>sure</u> Too High			No Hazard <i>p1-p1*p2</i>
p1	fails <i>p</i> 2	opens <i>1-p3</i>	No Hazard p1*p2-p1*p2*p3
		fails <i>p</i> 3	Hazard <i>p1*p2*p3</i>







- The Failure Mode, Effects and Criticality Analysis (FMECA) is a preventive method for the identification of problems, their risks and effects
- FMECA has the following goals
 - Detection of hazards and problems
 - Identification of potential risk
 - Quantification of risks
 - Determination of corrective measures
- FMECA can be performed as component FMECA (e.g. for a subsystem), as system FMECA (a complete system) or as process FMECA (e.g. for a development process)



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FMECA is done in the following steps

- Fault analysis: Collection of possible faults including available information about the type, causes and consequences
- · Risk evaluation with the aid of the risk priority number

RPN = occurrence probability * severity of consequences * probability of non-detection

- If for the three influencing factors a value between 1 and 10 is used (1= no risk, minor occurrence; 10 = high risk, high occurrence), the RPN is a value between 1 and 1000
- The risk priority number generates a ranking for the causes of faults
- Causes of faults with a high risk priority number are to be handled with priority



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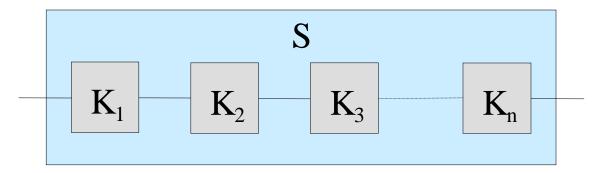


- Interconnection of all components of a system which are involved in performing the required function; represented as a flow chart
- RBDs distinguish only two states (intact/failed)
- Reliability function R(t)
 - F(t) gives the probability that at time t at least one failure has occurred; thus R(t) = 1 F(t) is the
 probability that at time t no failure has occurred yet



Reliability Block Diagrams Serial Connection

- n serial connected components ${\sf K}_{\sf i}.$ The system S fails if one of the components fails



$$R_{S}(t) = R_{K_{1}}(t) R_{K_{2}}(t) R_{K_{3}}(t) \dots R_{K_{n}}(t) = \prod_{i=1}^{n} R_{K_{i}}(t)$$

• Example:

Two components with $R_1 = R_2 = 0.8$: <u> $R_S = 0.64$ </u>

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Reliability Block Diagrams Parallel Connection

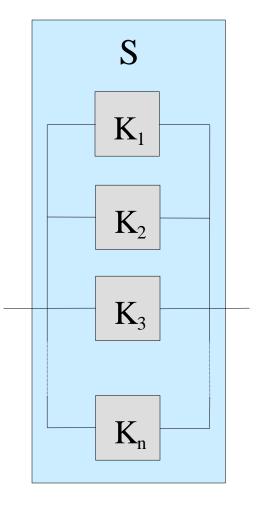
 n parallel connected components K_i. The system S fails if all components fail

$$F_{S}(t) = F_{K_{1}}(t) F_{K_{2}}(t) F_{K_{3}}(t) \dots F_{K_{n}}(t) = \prod_{i=1}^{n} F_{K_{i}}(t)$$

$$R_{S}(t) = 1 - F_{S}(t) = 1 - \prod_{i=1}^{n} F_{K_{i}}(t) = 1 - \prod_{i=1}^{n} (1 - R_{K_{i}}(t))$$

• Example:

Two components with $R_1 = R_2 = 0.8$: <u> $R_S = 0.96$ </u>

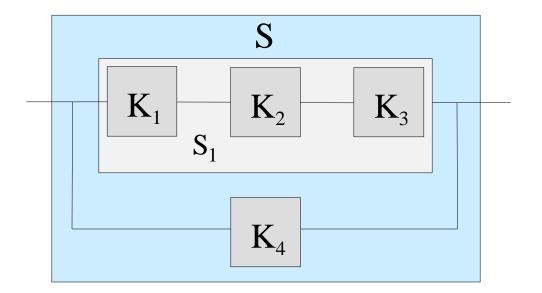






Reliability Block Diagrams Combined Serial/Parallel Connection

• Combinations of serial and parallel connections can be solved hierarchically





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• Example:

System S is a parallel connection of the subsystem S_1 with component K_4 The reliability of the subsystem S_1 is: $R_{S_1}(t) = R_{K_1}(t) R_{K_2}(t) R_{K_3}(t)$

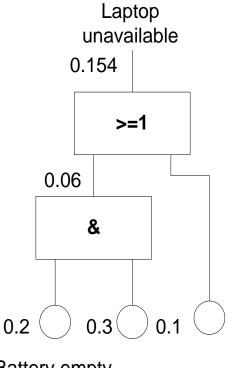
The reliability of the system S is: $R_{s}(t) = 1 - [(1 - R_{\kappa_{4}}(t)) (1 - R_{s_{1}}(t))]$ $= 1 - [(1 - R_{\kappa_{4}}(t)) (1 - R_{\kappa_{1}}(t) R_{\kappa_{2}}(t) R_{\kappa_{3}}(t))]$

All components have the reliability R = 0,8: $R_s = 0.9024$



Fault Tree Analysis





Battery empty Hardware No socket around

- Analysis method for the qualitative and quantitative evaluation of a *specific* failure of a system
- Deductive (backward searching)
- Graphical and intuitive technique
- Based on Boolean logic and combinatorics
- Widely accepted, captured in standards / handbooks
- Has been used and extended since 1961



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Markov Analysis



- Markov Analysis
 - Markov Chain
 - Markov Processes

• Petri Nets

- Condition/Event Petri nets
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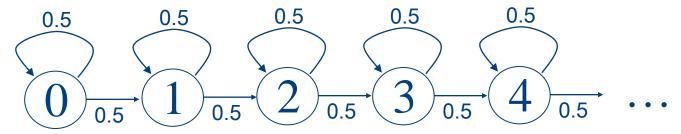


- Markov models are based on a description of the system behavior with state machines
- Common assumption of all Markov Models: The probability of the next state depends on the current state; it is independent from previous states, i.e. Markov models do not take into account the history
- Various Model types, e.g.:
 - Discrete time models (Markov chain)
 - Continuous time models; also called Markov processes





- Markov chains assume that state changes occur at discrete points in time
- Example: Throwing a coin *n* times and counting the results where we got the "front side" as the result of this experiment
- Obviously this can be modeled with the following Markov chain:



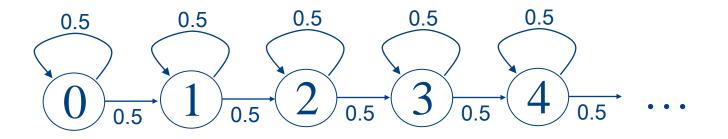
• If the current state is *i* then the probabilities to stay at state *i* or to enter state (*i*+1) are both 0.5. A state change may only occur at the discrete point in time, when the coin is thrown.



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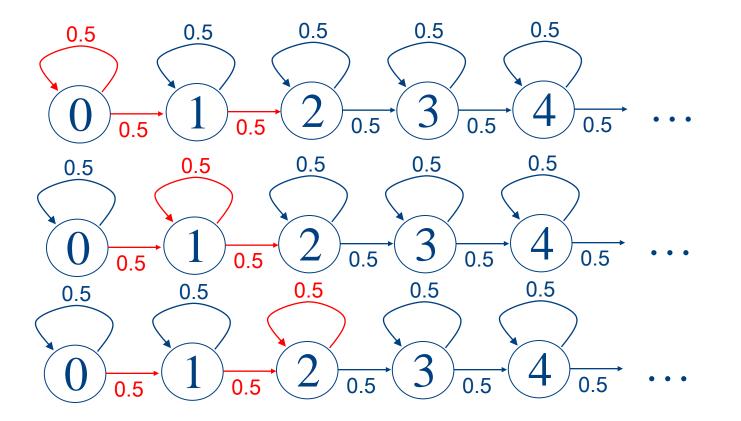
- What is the probably for 2 "front sides" after throwing the coin twice?
- Answer: There is one path of length 2, that leads into state 2, associated with probability (0.5 * 0.5) = 0.25





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- What is the probably for 2 "front sides" after throwing the coin three times?
- Answer: There are the following paths of length 3, that lead into state 2





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- Each of the three paths has probability (0.5 * 0.5 * 0.5) = 0.125
- The probability for 2 "front sides" after throwing the coin three times is 3 * 0.125 = 0.375

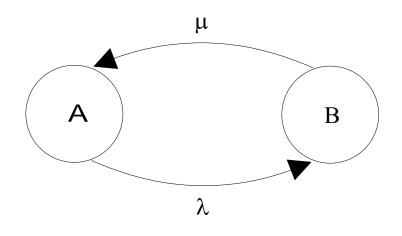


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Markov Processes



- Markov processes are continuous time models
- Example
 - A system with failure rate λ and repair rate μ is to be analyzed with the aid of a Markov model. The Markov model has the states A and B
 - A is the state where the system is intact. B is the state where the system failed
 - The system changes with the failure rate λ from the intact state into the failed state.
 With the repair rate μ it changes from the failed state into the intact operation





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$$\frac{dP_A(t)}{dt} = -\lambda P_A(t) + \mu P_B(t)$$

$$\frac{dP_B(t)}{dt} = \lambda P_A(t) - \mu P_B(t) = -\frac{dP_A(t)}{dt}$$

$$P_A(t) + P_B(t) = 1$$

$$P_A(t) = \frac{\mu}{\mu + \lambda} + (c - \frac{\mu}{\mu + \lambda}) e^{-(\mu + \lambda)t}$$

$$P_B(t) = 1 - P_A(t) = 1 - [\frac{\mu}{\mu + \lambda} + (c - \frac{\mu}{\mu + \lambda}) e^{-(\mu + \lambda)t}]$$

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• For t towards infinite one gets the steady state of the system

$$\lim_{t \to \infty} \mathsf{P}_{\mathsf{A}}(t) = \frac{\mu}{\mu + \lambda}$$

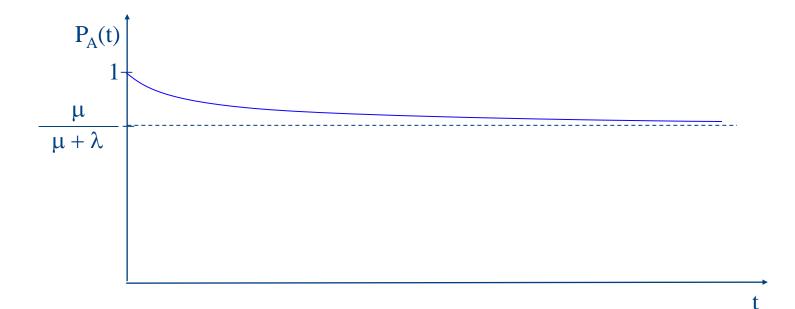
$$\lim_{t \to \infty} \mathsf{P}_{\mathsf{B}}(t) = 1 - \frac{\mu}{\mu + \lambda}$$

- If the repair rate is high compared to the failure rate the probability that the system is intact approaches 1
- If the repair rate is low compared to the failure rate the probability that the system is intact approaches zero



Markov Processes





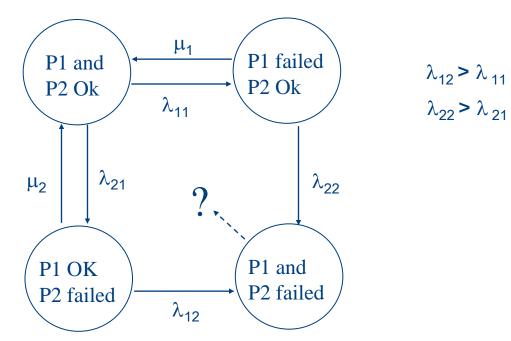
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 Let's assume we have to model a system that uses two pumps to pump water to a higher level. In normal operating mode each pump runs at 50% of its maximum power. The remaining pumps takes over the complete load, if one pump fails and thus gets additional stress, which increases its failure probability. How could that be modeled?



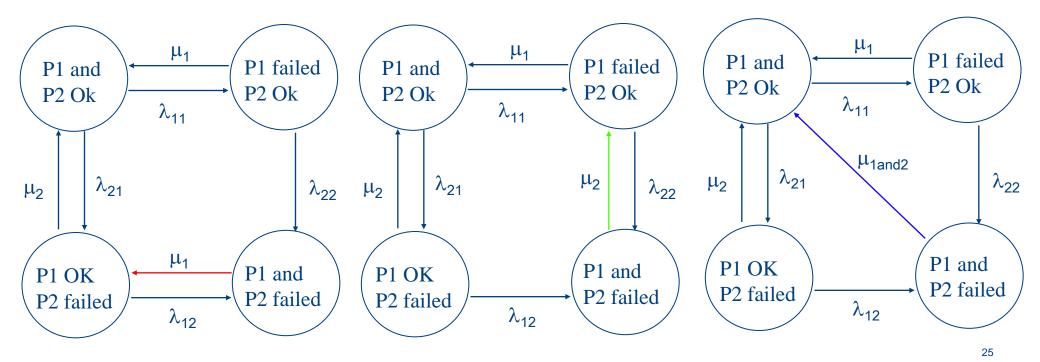


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Markov Processes



- Alternative repair strategies when both pumps have failed:
 - Repair P1 then switch on again,
 - Repair P2 then switch on again,
 - Repair P1 and P2 and then switch on again.



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Petri Nets



• Petri Nets

- Condition/Event Petri nets
- State/Transition Petri nets
- Predicate/Transistion Petri Nets / Coloured Petri Nets
- Timed Petri Net Types
 - SPN
 - GSPN
 - DSPN



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- The concept of Petri nets has its origin in Carl Adam Petri's dissertation *Kommunikation mit Automaten*, submitted in 1962 to the faculty of Mathematics and Physics at the Technische Universität Darmstadt, Germany
- Various Petri net types, e.g.:
 - Condition/Event Petri nets
 - State/Transition Petri nets
 - Predicate/Transistion Petri Nets / Coloured Petri Nets
 - Timed Petri Net Types
 - Stochastic delay
 - No delay
 - Deterministic delay





- A Petri Net N contains at least *places* (P), *transitions* (T) and a *flow relation* (F) as well as an initial marking (M_0) : N = (P, T, F, M₀):
- $P \cap T = \emptyset$
- $F \subseteq (P \times T) \cup (T \times P)$
- $M_0: P \rightarrow IN_0$





- State elements hold either one or no token
 - state elements represent conditions, which can be true or false
 - transition elements are represent local events
- Event is enabled if and only if
 - all its pre-conditions (connected by incoming arcs) are true
 - all its post-conditions (connected by outgoing arcs) are false
- An event occurrence negates its pre- and post-conditions
- Events with overlapping pre-conditions are in conflict
- Events with overlapping post-conditions are in contact



Petri Nets - Condition / Event Petri Nets Fundamentals



Petri nets

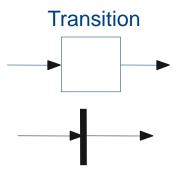
- Directed graph, which consists of two different kinds of nodes:
 - Places and Transitions

Places

represent a clipboard of information



Transitions describe the processing of information



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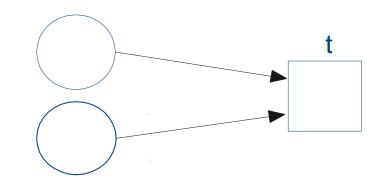
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Petri Nets - Condition / Event Petri Nets Fundamentals

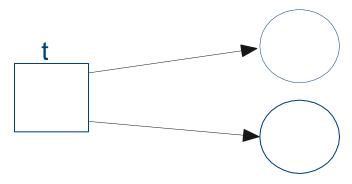


- Semantic
 - Arcs are only allowed between a node and the other kind of node.
 - Places from which arcs run to a transition t are called Input Places of t
 - Places to which arcs run from a transition t are called Output Places of t.

Input places of t



Output places of t





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Petri Nets - Condition / Event Petri Nets



C/E Net

- Objects, respectively tokens, are of **Boolean** data type
- Transitions are interpreted as Events
- Places are denoted as Conditions
- Each place is allowed to receive exactly one or no token.
- Additional firing condition:
- C A transition t can fire if each input space of t contains one token and if each output space of t is empty. When it fires, the token in each input space will be consumed respectively. One token will be assigned to each output space.

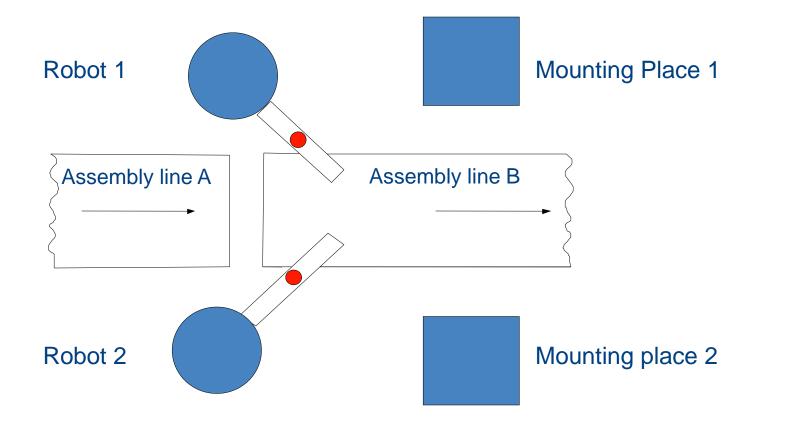


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Petri Nets - Condition / Event Petri Nets Example



- Example
 - 2 Robots assemble circuit boards with electronic devices, which are delivered on an assembly line A.



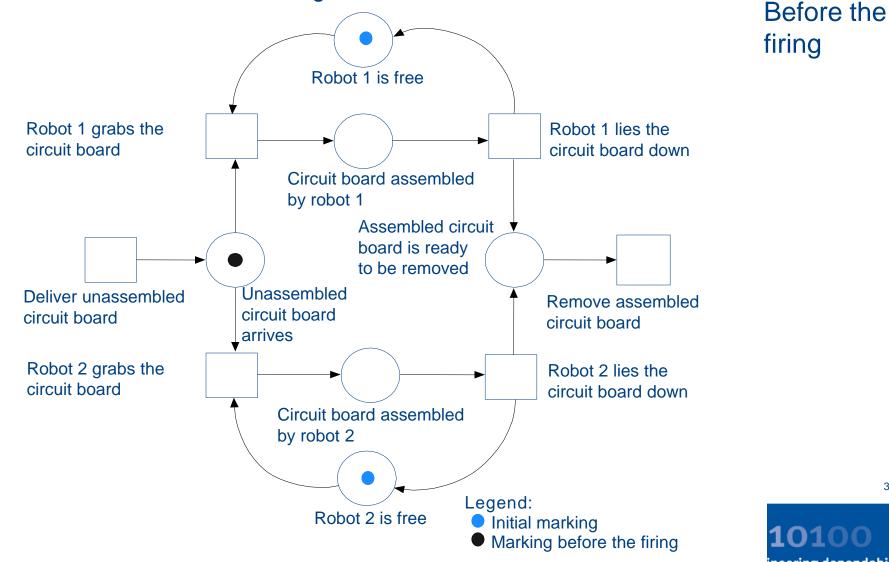
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Petri Nets - Condition / Event Petri Nets Example

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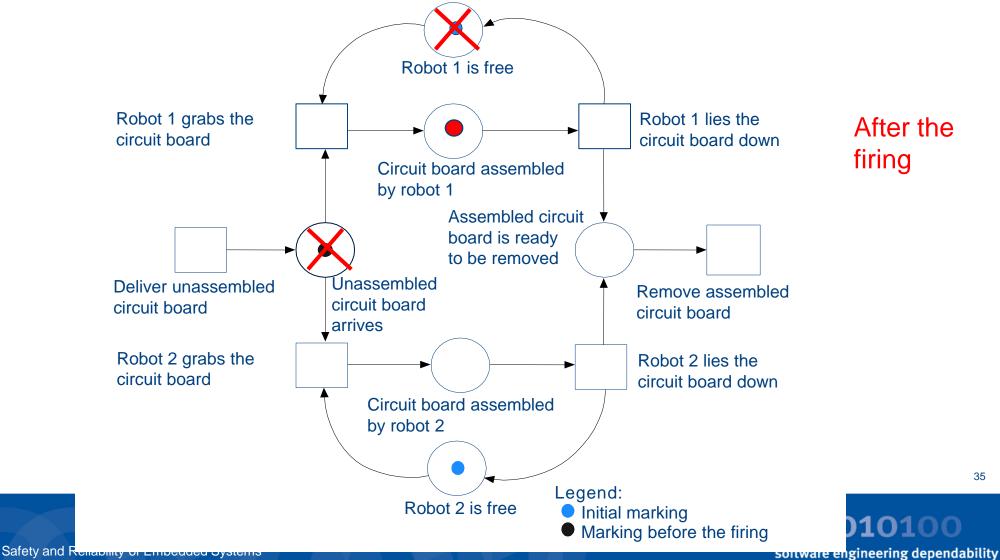
C/E Net of the assembling robot



Petri Nets - Condition / Event Petri Nets Condition/Event Net: Example



C/E Net of the assembling robot



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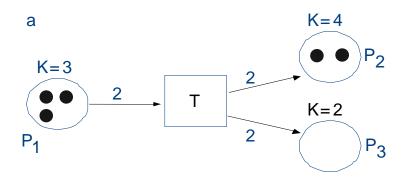
- P/T Nets (P/T Net, Place/Transition Net)
 - Places can obtain more than one token (in C/E nets only one token)
 - Transitions must release or add as many tokens when firing as the **weights** that are given on the arrows. (in C/E nets only one token)
 - If the capacity of a place is to be bigger than 1, this will be denoted as ***K** = ... « at the place.
 - The capacity defines the maximum number of tokens that may lie in one place.



Petri Nets Place/Transition Nets



• Firing with P/T Nets



- Before the firing
 - \bigcirc P₁: **3** Tokens
 - \bigcirc P₂: **2** Tokens
 - \bigcirc in P₃: no Token.

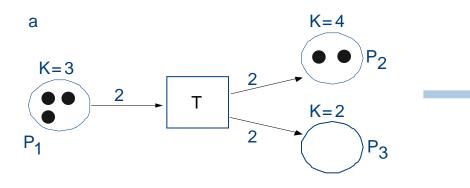


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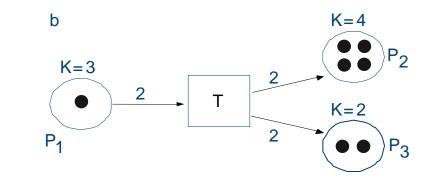
Petri Nets Place/Transition Nets

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• Firing with P/T Nets



- Before the firing
 - \bigcirc P₁: **3** Tokens
 - \bigcirc P₂: 2 Tokens
 - in P_3 : no Token.



- After the firing
 - \bigcirc P₁: **1** Token
 - \bigcirc P₂: 4 Tokens
 - in P_3 : 2 Tokens.

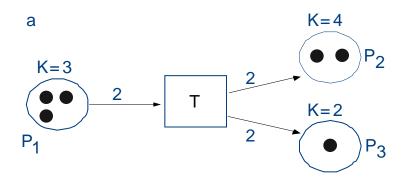


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Petri Nets Place/Transition Nets



• Firing conditions in P/T Nets



- T cannot fire because 3 Tokens would then lay in P_3
 - This is not allowed due to K = 2 of P_3 .

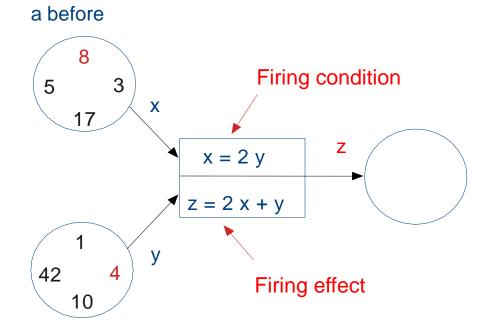


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Petri Nets Predicate/Transition Nets



- Pr/T Nets
 - Apply individual, »colored« tokens
 - C/E and P/T Nets apply only **»black**« tokens, which are all the same

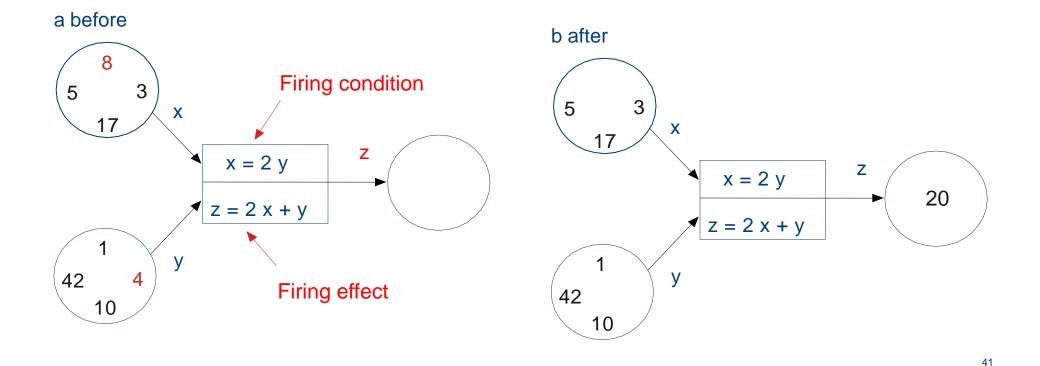


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Petri Nets Predicate/Transition Nets



- Pr/T Nets
 - Use individual, »colored« tokens
 - C/E and P/T Nets use only **»black**« tokens, which are all the same

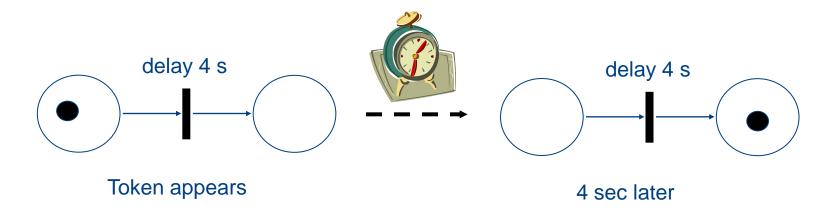


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Petri Nets Timed Petri Net Types: Simple approach

- To study performance and dependability issues of systems it is necessary to include a timing concept into the model.
- There are several possibilities to do this for a Petri net; however, the most common way is to associate a *firing delay* with each transition. This delay specifies the time that the transition has to be *enabled*, before it can actually fire:





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SPN (Stochastic Petri Net)

- If the delay is a random distribution function (exponential distribution), the resulting net class is called *stochastic Petri net*.
- GSPN (Generalised stochastic Petri Net)
- SPN plus *immediate transitions* (no delay) and inhibit edges.
 DSPN
- GSPN plus deterministic transitions (delay is fixed).

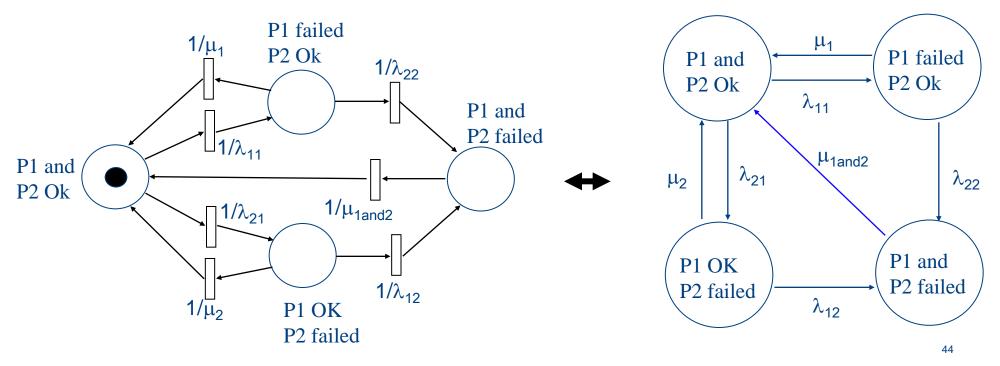


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SPN (Stochastic Petri Net)

- Delay is exponentially distributed
- Can be transformed into an equivalent Markov Process

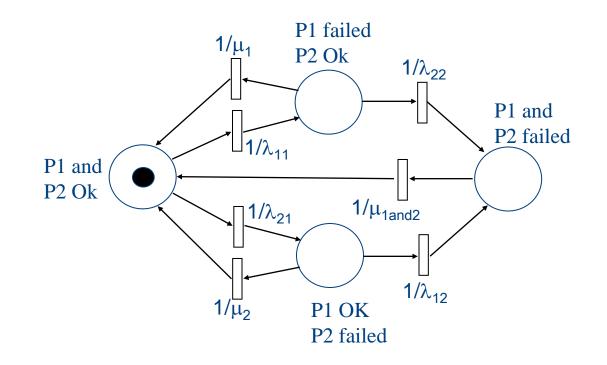


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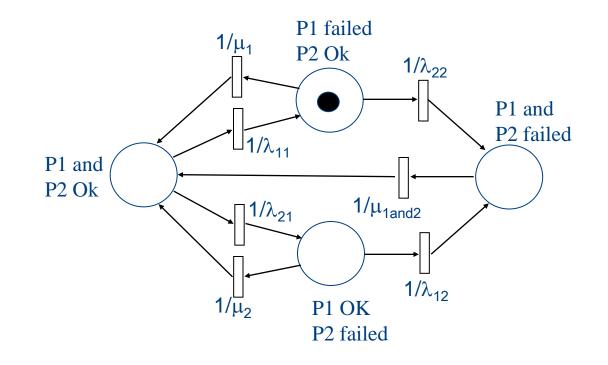
Possible markings: Initial



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Petri Nets Timed Petri Net Types (SPN)





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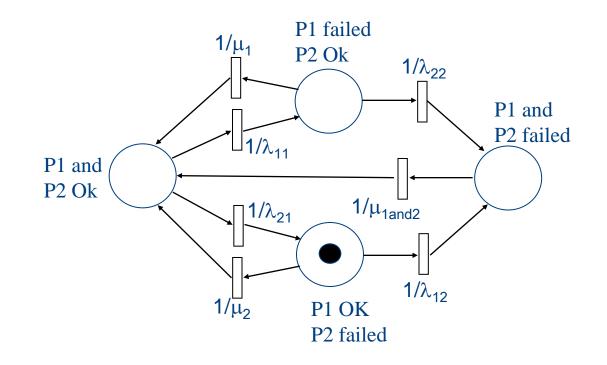
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Petri Nets Timed Petri Net Types (SPN)





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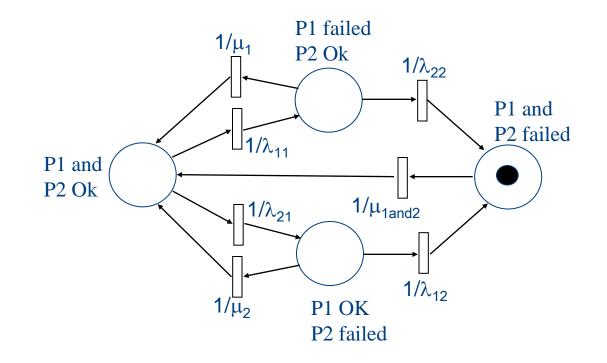
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Petri Nets Timed Petri Net Types (SPN)

Possible markings: Both failed



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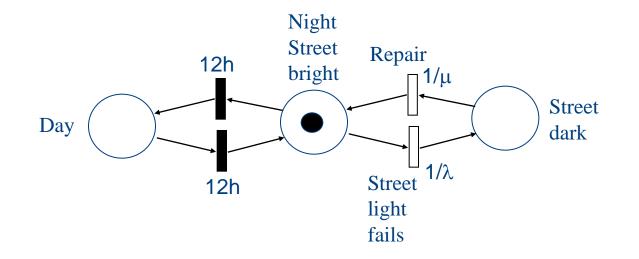
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• Exponentially distributed delay + *immediate transitions* (no delay) + *deterministic transitions* (delay is fixed) and inhibit arcs



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